

#### description

The TMS27C128 series are 131,072-bit, ultraviolet-light erasable, electrically programmable read-only memories. These devices are fabricated using HVCMS technology for high speed and simple interfacing with MOS and bipolar circuits. All inputs (including program data inputs) can be driven by Series 74 TTL circuits without the use of external pull-up resistors, and each output can drive one Series 74 TTL circuit without external resistors. The data outputs are three-state for connecting multiple devices to a common bus. The TMS27C128 is pin compatible with existing 28-pin ROMs and EPROMs. It is offered in a dual-in-line ceramic package (DIP) rated for operation from 0°C to 70°C.

Since these EPROMs operate from a single 5-V supply (in the read mode), they are ideal for use in microprocessor-based systems. One other (12.5 V) supply is needed for programming, but all programming signals are TTL level. For programming outside the system, existing EPROM programmers can be used. Locations may be programmed singly, in blocks, or at random.

#### operation

There are seven modes of operation for the TMS27C128 listed on the following page. Read mode requires a single 5-V supply. All inputs are TTL level except for VPP during programming (12.5 V) and 12.5 V (A9) for signature mode.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

TEXAS  
INSTRUMENTS

switching characteristics over full ranges of recommended operating conditions (see Note 4)

PARAMETER	TEST CONDITIONS (SEE NOTES 4 AND 6)	'27C128-1 '27C128-15 '27C128-20 '27C128-25	'27C128 UNIT
$t_{\text{gl(A)}}$		MIN 150 MAX 200	ns
$t_{\text{gl(E)}}$		MIN 200 MAX 250	ns
$t_{\text{en(G)}}$	$C_L = 100 \text{ pF}$ 1 Series 74 TTL Load. Input $t_{\text{r}} \leq 20 \text{ ns}$ . Input $t_{\text{f}} \leq 20 \text{ ns}$	MIN 150 MAX 200	ns
$t_{\text{dis}}$	E, whichever occurs first <sup>1</sup> Output date valid time after change of address, E, or G, whichever occurs first <sup>1</sup>	0 60 0 80 0 60	ns
$t_{\text{f(A)}}$		0 0 0 0	ns

PARAMETER	TEST CONDITIONS (SEE NOTES 4 AND 6)	'27C128-3 '27C128-30 '27C128-45	'27C128-4 '27C128-50
$t_{\text{gl(A)}}$		MIN 300 MAX 450	ns
$t_{\text{gl(E)}}$		MIN 300 MAX 450	ns
$t_{\text{en(G)}}$	$C_L = 100 \text{ pF}$ 1 Series 74 TTL Load. Input $t_{\text{r}} \leq 20 \text{ ns}$ . Input $t_{\text{f}} \leq 20 \text{ ns}$	MIN 120 MAX 150	ns
$t_{\text{dis}}$	E, whichever occurs first <sup>1</sup> Output date valid time after change of address, E, or G, whichever occurs first <sup>1</sup>	0 105 0 130	ns
$t_{\text{f(A)}}$		0 0 0	ns

<sup>1</sup>Value calculated from 0.5 V delta to measured output level. This parameter is only sampled and not 100% tested.

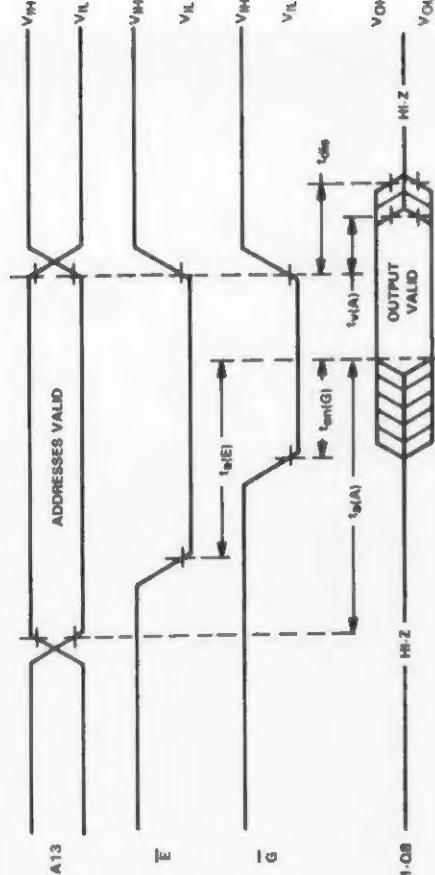
recommended timing requirements for programming. TA = 25°C, VCC = 6 V, VPP = 12.5 V  
(see Note 4)

	MIN	NOM	MAX	UNIT
$t_{\text{w(IPGM)}}$	Initial program pulse duration	0.95	1	1.05
$t_{\text{w(FPGM)}}$	Final pulse duration	2.85	78.75	ms
$t_{\text{au(A)}}$	Address setup time	2		$\mu\text{s}$
$t_{\text{au(E)}}$	E setup time	2		$\mu\text{s}$
$t_{\text{au(G)}}$	G setup time	2		$\mu\text{s}$
$t_{\text{dis(G)}}$	Output disable time from G	0	130	ns
$t_{\text{en(G)}}$	Output enable time from G	0	150	ns
$t_{\text{au(D)}}$	Data setup time	2		$\mu\text{s}$
$t_{\text{au(VPP)}}$	VPP setup time	2		$\mu\text{s}$
$t_{\text{au(VCC)}}$	VCC setup time	2		$\mu\text{s}$
$t_{\text{hi(A)}}$	Address hold time	0		$\mu\text{s}$
$t_{\text{hi(D)}}$	Data hold time	2		$\mu\text{s}$

NOTES: 4. For all switching characteristics and timing measurements, input pulse levels are 0.65 V to 2.2 V and  $V_{\text{PP}} = 12.5 \text{ V} \pm 0.5 \text{ V}$  during programming. Input and output timing reference levels are 0.8 V and 2 V.

5. Common test conditions apply for  $t_{\text{dis(G)}}$  except during programming.

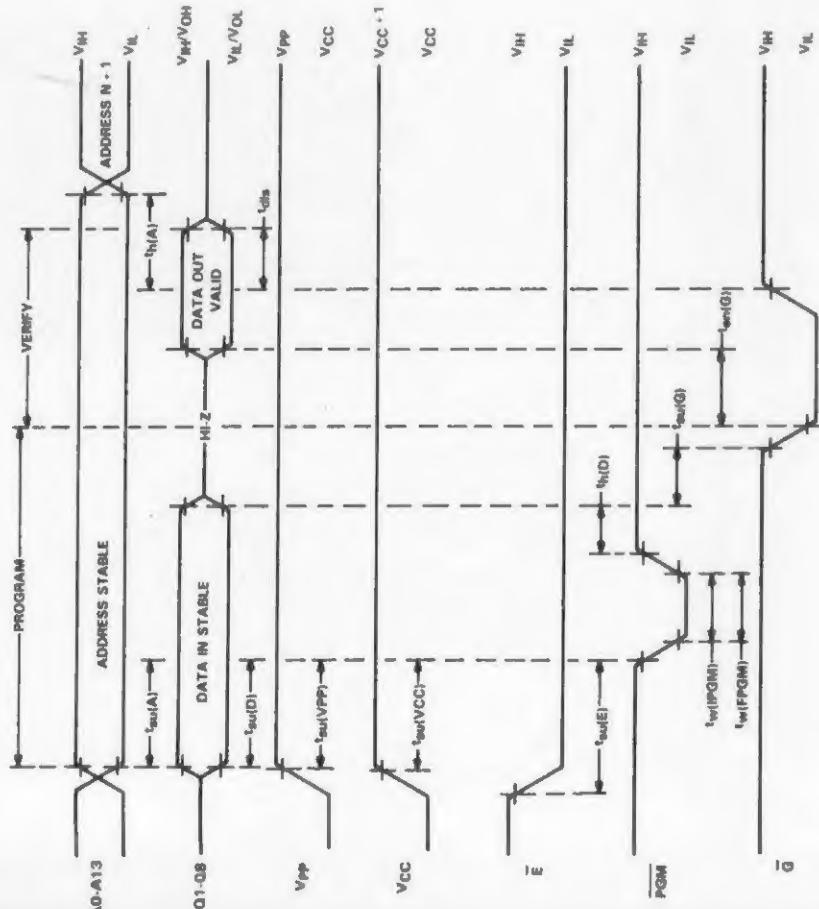
FIGURE 2. OUTPUT LOAD CIRCUIT



read cycle timing

EPROMs/PROMs

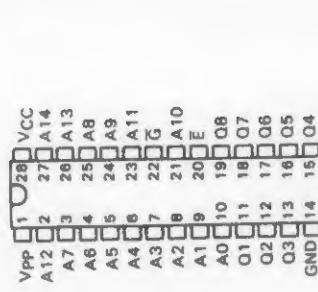
## Program cycle timing



## • Organization . . . 32K x 8

- Single 5-V Power Supply
- Pin Compatible with Existing 128K and 268K EPROMs
- All Inputs/Outputs Fully TTL Compatible
- Max Access/Min Cycle Time
  - '27C256-1. '27C256-17 170 ns
  - '27C256-2. '27C256-20 200 ns
  - '27C256. '27C256-25 250 ns
  - '27C256-3. '27C256-30 300 ns
  - '27C256-4. '27C256-45 450 ns
- HVCMOS Technology
- 3-State Output Buffers
- 400 mV Guaranteed DC Noise Immunity with Standard TTL Loads
- Low Power Dissipation (VCC = 5.25 V)
  - -Active . . . 210 mW Worst Case
  - -Standby . . . 1.4 mW Worst Case (read, write, and sleep)

J PACKAGE



PIN NOMENCLATURE

AOA14	Address Inputs
$\bar{E}$	Chip Enable/Power Down
$\bar{G}$	Output Enable
GND	Ground
	Outputs
Q1-Q8	5-V Power Supply
VCC	12.5-V Power Supply
V <sub>DD</sub>	

description

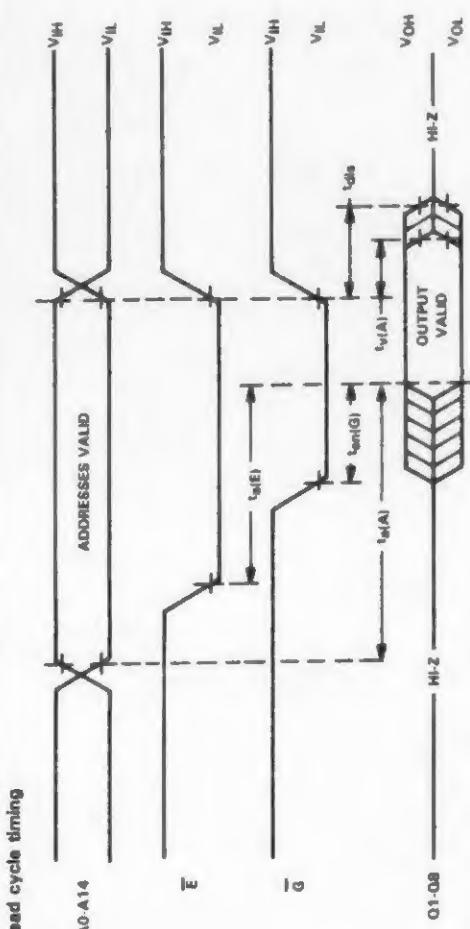
The TMS27C256 series are 262,144-bit, ultraviolet-light erasable, electrically programmable read-only memories. These devices are fabricated using HVCMOS technology for high speed and simple interface with MOS and bipolar circuits. All inputs (including program data inputs) can be driven by Series 74 TTL circuits without the use of external pull-up resistors, and each output can drive one Series 74 TTL circuit without external resistors. The data outputs are three state for connecting multiple devices to a common bus. The TMS27C256 is pin compatible with existing 28-pin ROMs and EPROMs. It is offered in a dual-in-line package with a maximum operating frequency of 100 ns and a maximum operating temperature range of -40°C to 70°C.

Since these EPROMs operate from a single 5-V supply (in the read mode), they are ideal for use in microprocessor-based systems. One other (12.5 V) supply is needed for programming, but all programming signals are TTL level. For programming outside the system, existing EPROM programmers can be used. Locations may be programmed singly, in blocks, or at random.

## Operation

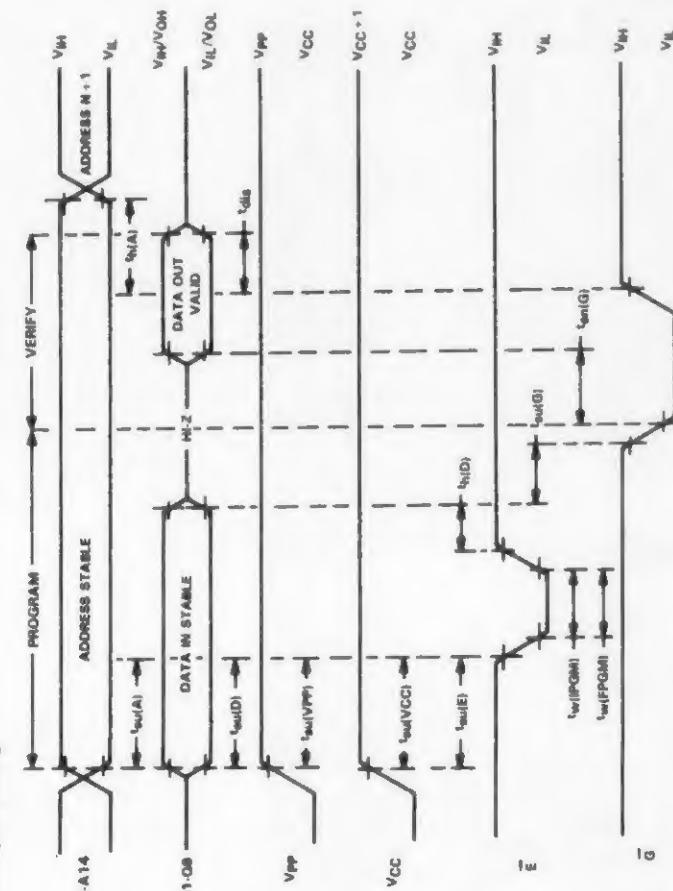
There are seven modes of operation for the TMS27C256 listed on the following page. Read mode requires a single 5-V supply. All inputs are TTL level except for V<sub>PP</sub> during programming (112.5 V) and 12 V on A9 for signature mode.

- Organization . . . 64K x 8
- Single 5-V Power Supply
- Pin Compatible with Existing
- All Inputs/Outputs Fully TTL
- Max Access/Min Cycle Time
  - '27C512-2. . . . . 27C512-2.2
  - '27C512. . . . . 27C512-12
  - '27C512-3. . . . . 27C512-31
  - '27C512-4. . . . . 27C512-41
- HVCMS Technology
- 3-State Output Buffers
- 400 mV Guaranteed DC Noise with Standard TTL Loads
- Low Power Dissipation (Vcc)
  - Active . . . . . 263 mW
  - Standby . . . . . 1.4 mW



### Read cycle timing

### Program cycle timing



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## EPROMs/PROMs

EFROMS/PRIM

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J PACKAGE  
(TOP VIEW)

A15	1	28	VCC
A12	2	27	A14
A7	3	26	A13
A6	4	25	A8
A5	5	24	A9
		A4	6
		A3	7
		A2	8
		A1	9
		A0	10
		Q1	11
		Q2	12
		Q3	13
		GND	14
			15
			04

PIN NOMENCLATURE	
A0 A15	Address Inputs
Ē	Chip Enable Power
GND	Ground
Q1 Q8	Outputs
VCC	5 V Power Supply
Ć VPP	12.5 V Power Supply
	Output Enable
	Output Enable

EPRM®/PRM®

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The **TMX27C512** series are 524,288-bit, ultraviolet light erasable, electrically programmable read-only memories. These devices are fabricated using HVCMOS technology for high speed and simple interface with MOS and bipolar circuits. All inputs (including program data inputs) can be driven by Series 74 TTL circuits without the use of external pull up resistors, and each output can drive one Series 74 TTL circuit without external resistors. The data outputs are three state for connecting multiple devices to a common bus. The TMX27C512 is pin compatible with existing 28-pin ROMs and EPROMs. It is offered in a dual-in-line ceramic package (J suffix) rated for operation from 0°C to 70°C.

Since these EPROMs operate from a single 5-V supply (in the read mode), they are ideal for use in microprocessor-based systems. One other (12.5 V) supply is needed for programming, but all programming signals are TTL level. For programming outside the system, existing EPROM programmers can be used.

**PRODUCT PREVIEW** documents contain information on products in the feasibility or design phase of development. Characteristic data and other specifications are design goals. Test instruments reserves the right to change or discontinue them products without notice.